



Traceability Japan TC Chapter Meeting Summary and Minutes

Japan Standards Summer Meetings 2025

Wednesday, June 11, 2025, 10:00AM – 1:00PM JST

SEMI Japan, Tokyo, Japan / Official Virtual TC Chapter Meeting (Hybrid)

TC Chapter Announcements

Next TC Chapter Meeting

TBD in conjunction with SEMICON Japan 2025.

Tokyo Big Sight, Tokyo, Japan/ OVTCCM (Hybrid)

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Yoichi Iga (Self) / Hirokazu Tsunobuchi (GENETEC)

SEMI Staff: Nahoko Koga (SEMI Japan)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
<i>Self</i>	<i>Iga</i>	<i>Yoichi</i>	<i>Omron</i>	<i>Yoshitake</i>	<i>Naoki</i>
Tokyo Electron	Hayashi	Haruna	<i>PwC Consulting LLC</i>	<i>Ogawa</i>	<i>Hiromi</i>
<i>National Institute of Advanced Industrial Science and Technology</i>	<i>Kobara</i>	<i>Kazukuni</i>	<i>Hitachi High-Tech</i>	<i>Toyoshima</i>	<i>Yuko</i>
<i>Micron</i>	<i>Garrett</i>	<i>Mike</i>	<i>Okinawa Open Laboratory</i>	<i>Hayashi</i>	<i>Kenji</i>
<i>Tokyo Electron</i>	<i>Hama</i>	<i>Naoya</i>	<i>Okinawa Open Laboratory</i>	<i>Tsujikawa</i>	<i>Mark</i>
<i>KOKUSAI ELECTRIC</i>	<i>Matsuda</i>	<i>Mitsuhiro</i>	<i>Tokyo Electron</i>	<i>Mashiro</i>	<i>Supika</i>
<i>SCREEN Semiconductor Solutions</i>	<i>Nishimura</i>	<i>Takayuki</i>	<i>SATO</i>	<i>Hisashi</i>	<i>Kakuno</i>
<i>Samsung Electronics</i>	<i>Bruce</i>	<i>Eric</i>	<i>Samsung Electronics</i>	<i>CHOI</i>	<i>JINHYEOK</i>
<i>Keyence Corporation</i>	<i>Mori</i>	<i>Daiki</i>	SEMI Japan	Kanno	Hirofumi
<i>GENETEC</i>	<i>Tsunobuchi</i>	<i>Hirokazu</i>	SEMI Japan	Yoshida	Akiko
<i>Murata Machinery</i>	<i>Tominaga</i>	<i>Tadamasa</i>	SEMI Japan	Koga	Nahoko

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
None		

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
None	

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
7335	New Standard: Specification for Traceability Identification Label of Component Parts	Passed as balloted

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Ratification Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>ISC A&R Action</i>	<i>A&R Forms</i>
None			

Note 1: **Passed** Ratification ballots will be submitted to SEMI publication for final processing.

Note 2: **Failed** Ratification ballots were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 6 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
7335	SNARF and Letter Ballot Authorization for Cycle 3, 2025	Parts & Materials ID TF	New Standard: Specification for Traceability Identification Label of Component Parts

Table 7 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 8 Authorized Ballots

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
None			

Table 9 SNARF(s) Granted a One-Year Extension

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
None			

Table 10 SNARF(s) Cancelled

<i>#</i>	<i>TF</i>	<i>Title</i>
None		

Table 11 Standard(s) to receive Inactive Status

<i>Standard Designation</i>	<i>Title</i>
None	

Table 12 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
Trace_20250611_01	SEMI staff	To forward ballot review results of Doc.#7335 to the ISC A&R SC for procedural review.

Table 13 Previous Meeting Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
7301	TF leaders and those involved	Make a Ballot Draft document for Cycle 3, 2025 →Closed <i>Staff Note:</i> <i>SNARF 7301 was changed to SNARF 7335 to change the scope. Doc.#7335 was submitted for Cycle 3, 2025.</i>

1 Welcome, Reminders, and Introductions

Yoichi Iga (Self) called the meeting to order at 10:00AM. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01_Required Meeting Elements March 2024_J

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: Approve the minutes with one correction
By / 2nd: By: Takayuki Nishimura (SCREEN Semiconductor Solutions)
 Second By: Hirokazu Tsunobuchi (GENETEC)
Discussion: Correction of company name:
 SCREEN Semiconductor Solution→SCREEN Semiconductor Solutions
Vote: 13-Y 0-N. Motion passed.

Attachment: 02_Traceability Mins_20241204_v2

3 Liaison Reports

3.1 Japan Regional Standards Committee (JRSC)

Hirofumi Kanno (SEMI Japan) reported for the JRSC that the meeting was held on Thursday, April 17. Topics included:

- Daisuke Sado (Eagle industry) was appointed by the ISC to be a co-chair of JRSC. With this, Tadahiro Furukawa (Yamagata University) stepped down from co-chair position.
- The Planning Meeting will be held on Thursday, August 28, inviting all the TF leaders as well as TC co-chairs to deepen knowledge or insights regarding standardization. The theme this year would be “Transparency in the Supply Chain and SEMI Standards.” More details will be announced as soon as they are finalized.

3.2 Global Coordinating Subcommittee (GCS)

Nahoko Koga (SEMI Japan) reported for the GCS that SNARF 7335, New Standard: Specification for Traceability Identification Label of Component Parts as well as its ballot submission for Cycle 3, 2025 were approved by the GCS.

3.3 Traceability North America TC Chapter

Nahoko Koga (SEMI Japan) reported for the Traceability North America TC Chapter. Of note:

- Last meeting was held on June 5th, 2025. The next meeting is to be determined.
- Doc.#7234, New Standard: Specification for Electronic Supply Chain Traceability Using Distributed Ledger Technology passed ballot review with editorial changes.
- SEMI T23-0420 - Specification for Single Device Traceability for the Supply Chain was subject to 5-year review.

Attachment: 03_NA Liaison Report - Traceability June-2025

4 SEMI Staff Reports

Nahoko Koga (SEMI Japan) gave the SEMI Staff Report. Of note:

- SEMICON West 2025 will be held in Phoenix, Arizona in October. The venue of SEMICON West will alternate between Phoenix and San Francisco every October thereafter.
- All Standards Task Forces shall use Connect@SEMI to host documents that are currently in development. However, the ISC Regulations SC recommended to postpone enforcement of implementation until next Regs/PM revision (which is currently aimed to become effective by NA Summer meeting in June). The Regs SC is working with SEMI to update both Connect@SEMI and rules so that they are aligned each other.
- SEMI University Japan Store launched in June 2024, which provides SEMI Japan original e-learning courses with Japanese audio or subtitles including SEMI Standards tutorials.

Attachment: 04_Staff Report Feb 2025 v2_ay

5 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

5.1 Document # 7335, New Standard: Specification for Traceability Identification Label of Component Parts

- This document **passed** as balloted. Refer to attachment for more details.

Attachment: 05_7335_Ballot Review

6 Subcommittee and Task Force Reports

6.1 Blockchain TF

Hirokazu Tsunobuchi (GENETEC) reported for the Blockchain Task Force. The Blockchain Analytics WG, subordinate to this Task Force is working on some additional texts to SEMI T25 - Specification for Blockchain for Semiconductor Supply Chain Traceability.

6.2 5-Year Review TF

Hirokazu Tsunobuchi (GENETEC) reported for the 5-Year Review Task Force. There are no activities to be reported.

6.3 Parts & Materials ID TF

Hirokazu Tsunobuchi (GENETEC) reported for the Parts & Materials ID Task Force. The Task Force met in May to discuss the voting results of Doc.#7335, New Standard: Specification for Traceability Identification Label of Component Parts.

Attachment: 06_20250611Traceability_TC_TaskForceReport

7 Old Business

7.1 Project Period Review

No SNARF will be expiring soon.

7.2 5-Year Review

No document is subject to 5-year review within this year.

8 New Business

None

9 Action Item Review

9.1 Open Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
7301	TF leaders and those involved	Make a Ballot Draft document for Cycle 3, 2025 →Closed <i>Staff Note:</i> <i>SNARF 7301 was changed to SNARF 7335 to change the scope.</i> <i>Doc.#7335 was submitted for Cycle 3, 2025.</i>

9.2 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
Trace_20250611_01	SEMI staff	To submit the result of Doc.#7335 ballot review to the ISC A&R for procedural review.

10 Next Meeting and Adjournment

The next meeting is tentatively scheduled for the week of December 17-20, 2025 in conjunction with SEMICON Japan 2025. Schedule details TBD. See <http://www.semi.org/standards-events> for the current list of events.

Adjournment: [13:00 JST].

Respectfully submitted by:

Nahoko Koga

Standards & EHS



SEMI Japan

Phone: +81-3-3222-6018

Email: nkoga@semi.org

Minutes tentatively approved by:

Yoichi Iga (Self), Co-chair	July 7, 2025
Hirokazu Tsunobuchi (GENETEC), Co-chair	July 8, 2025

Table 14 Index of Available Attachments^{#1}

<i>Title</i>	<i>Title</i>
01_Required Meeting Elements March 2024_J	02_Traceability Mins_20241204_v2
03_NA Liaison Report - Traceability June-2025	04_Staff Report Feb 2025 v2_ay
05_7335_Ballot Review	06_20250611Traceability_TC_TaskForceReport

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.